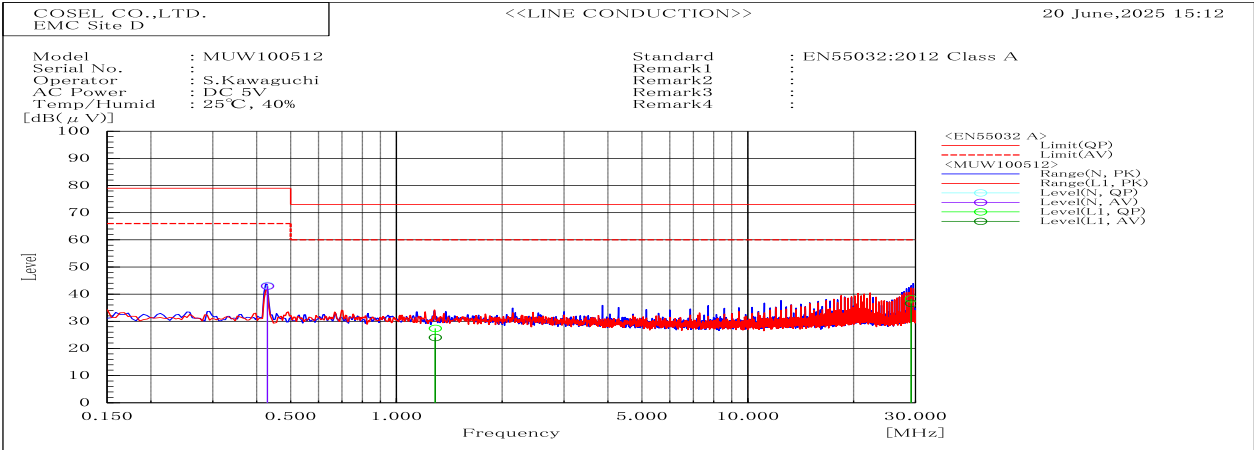
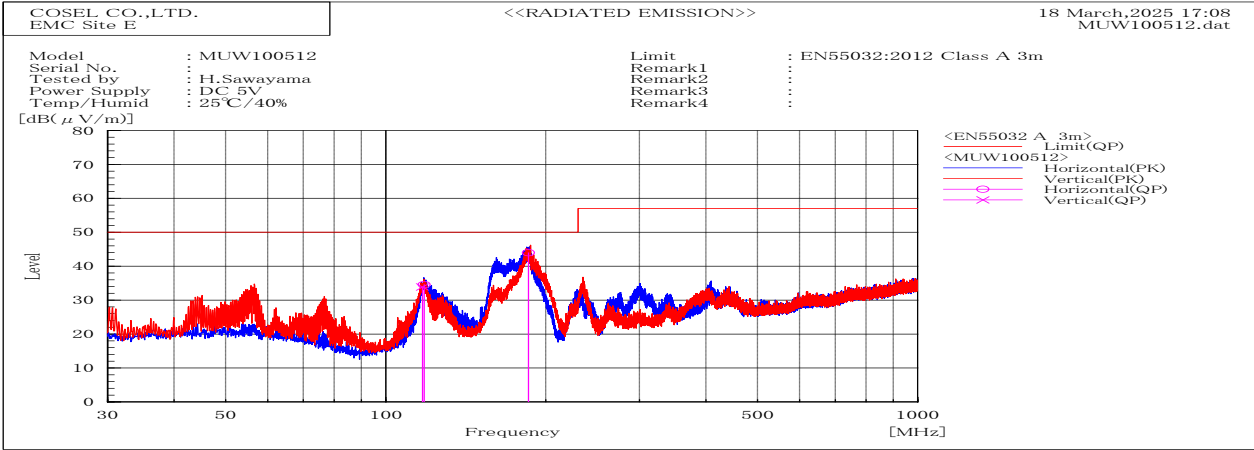


DATA SHEET		Date	20-Jun-25
Model	MUW100512	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi



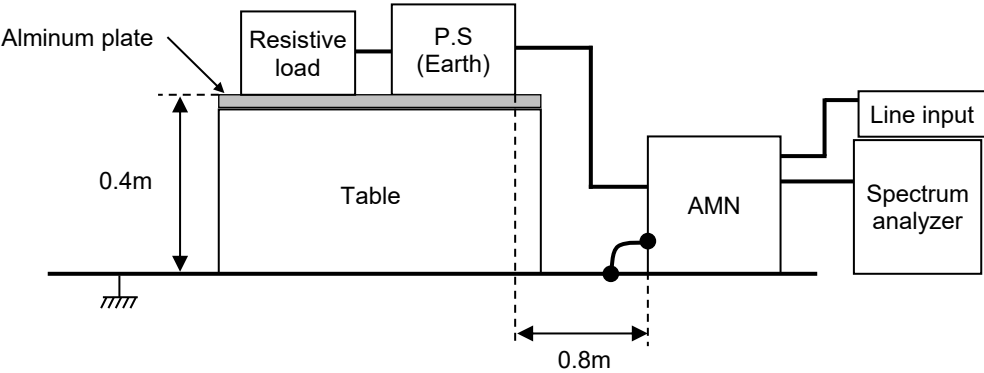
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
1.29	L1	27.4	24.1	73	60	45.6	35.9	Pass	
29.199	L1	38.3	36.6	73	60	34.7	23.4	Pass	
0.43	N	43.2	43	79	66	35.8	23	Pass	



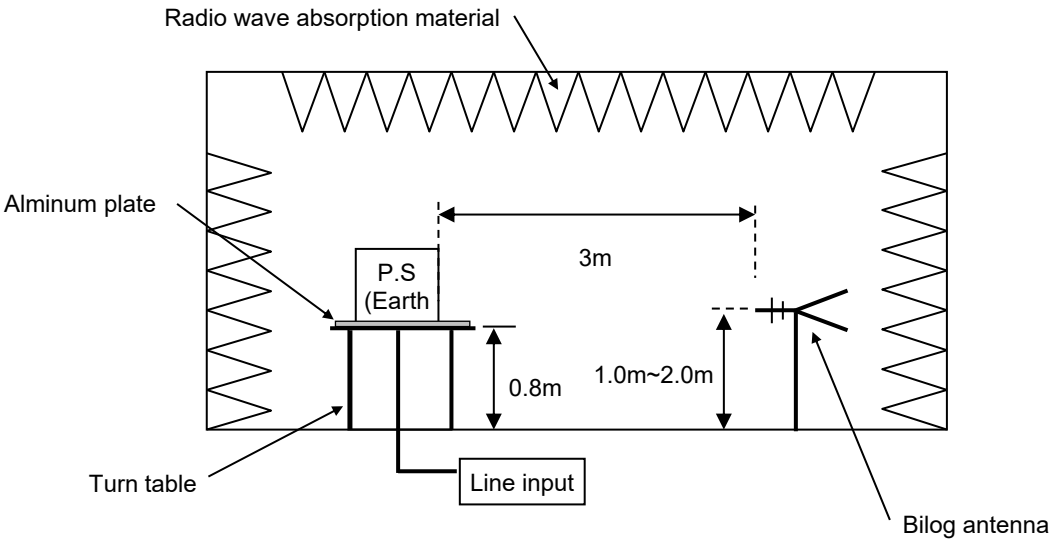
Frequency MHz	Polarization	Stability	Level dB(uV/m)		Limit dB(uV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP		QP				
185.462	H	Stable	44	50	6	Pass	200	345.3		
117.218	V	Stable	33.9	50	16.1	Pass	132.4	156.7		
118.078	H	Stable	34.6	50	15.4	Pass	181.7	353.1		

DATA SHEET		Date	20-Jun-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

Test : EMI  
Model Name: MUW10□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

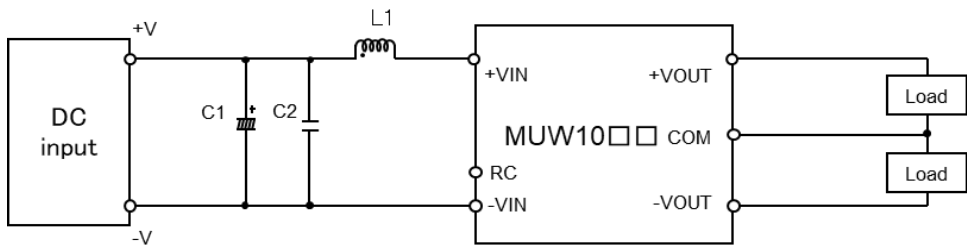


Fig.1 MUW10□□ Testing circuitry

C1 :	MUW1005□	25V 1500 $\mu$ F	Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MUW1012□	50V 100 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUW1024□	—	—
	MUW1048□	—	—
C2 :	MUW1005□	16V 22 $\mu$ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUW1012□	25V 10 $\mu$ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUW1024□	50V 4.7 $\mu$ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUW1048□	100V 2.2 $\mu$ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUW1005□	5000mA 2.2 $\mu$ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUW1012□	3500mA 4.7 $\mu$ H	Inductor(LQH5BPN4R7N38 MURATA MANUFACTURING)
	MUW1024□	1600mA 22 $\mu$ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)
	MUW1048□	1100mA 47 $\mu$ H	Inductor(LQH5BPN470M38 MURATA MANUFACTURING)